Applicant(s)/Patent Under Reexamination Application/Control No. 10/605,636 LEE ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Ryan M. Stiglic 2112 **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0148450 A1	07-2004	Chen et al.	710/313
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